

January 2010

FDZ192NZ

N-Channel 1.5 V Specified PowerTrench® Thin WL-CSP MOSFET 20 V, 5.3 A, 39 m Ω

Features

- Max $r_{DS(on)} = 39 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_{D} = 2.0 \text{ A}$
- Max $r_{DS(on)} = 43 \text{ m}\Omega$ at $V_{GS} = 2.5 \text{ V}$, $I_D = 2.0 \text{ A}$
- Max $r_{DS(on)} = 49 \text{ m}\Omega$ at $V_{GS} = 1.8 \text{ V}$, $I_{D} = 1.0 \text{ A}$
- Max $r_{DS(on)} = 55 \text{ m}\Omega$ at $V_{GS} = 1.5 \text{ V}$, $I_D = 1.0 \text{ A}$
- Occupies only 1.5 mm² of PCB area.Less than 50% of the area of 2 x 2 BGA
- Ultra-thin package: less than 0.65 mm height when mounted to PCR
- HBM ESD protection level > 2200V (Note3)
- RoHS Compliant

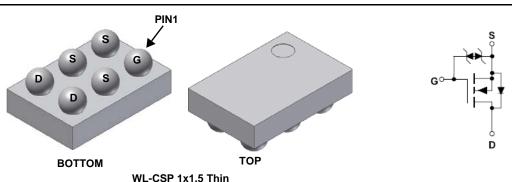


General Description

Designed on Fairchild's advanced 1.5 V PowerTrench® process with state of the art "fine pitch" WLCSP packaging process, the FDZ192NZ minimizes both PCB space and $r_{\text{DS}(\text{on})}.$ This advanced WLCSP MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile packaging, low gate charge, and low $r_{\text{DS}(\text{on})}.$

Applications

- Battery management
- Load switch
- Battery protection



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage			20	V
V _{GS}	Gate to Source Voltage			±8	V
	-Continuous	T _A = 25°C	(Note 1a)	5.3	۸
I _D	-Pulsed			15	— A
D	Power Dissipation	T _A = 25°C	(Note 1a)	1.9	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1b)	0.9	VV
T _J , T _{STG}	Operating and Storage Junction Temper	rature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	65	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	133	*C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
8	FDZ192NZ	WL-CSP 1x1.5 Thin	7 "	8 mm	5000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	octeristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		10		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.4	0.7	1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-3		mV/°C
		$V_{GS} = 4.5 \text{ V}, I_D = 2.0 \text{ A}$		26	39	
	Static Drain to Source On Resistance	$V_{GS} = 2.5 \text{ V}, I_D = 2.0 \text{ A}$		29	43	
roo()		$V_{GS} = 1.8 \text{ V}, I_D = 1.0 \text{ A}$		33	49	mΩ
r _{DS(on)}	Static Brain to Godice On Resistance	$V_{GS} = 1.5 \text{ V}, I_D = 1.0 \text{ A}$		38	55	11122
		$V_{GS} = 4.5 \text{ V}, I_D = 2.0 \text{ A},$ $T_J = 125 \text{ °C}$		31	47	
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 5.3 \text{ A}$		36		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40 V V 0 V	915	1220	pF
C _{oss}	Output Capacitance	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	145	195	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	100	150	pF

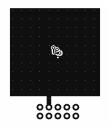
Switching Characteristics

t _{d(on)}	Turn-On Delay Time		6.5	13	ns
t _r	Rise Time	V _{DD} = 10 V, I _D = 5.3 A,	4	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$	50	80	ns
t _f	Fall Time		20	32	ns
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 10 \text{ V},$	12	17	nC
Q _{gs}	Gate to Source Charge	$V_{DD} = 10 \text{ V},$ $I_{D} = 5.3 \text{ A}$	1.3		nC
Q_{gd}	Gate to Drain "Miller" Charge	1D = 0.0 A	2.3		nC

Drain-Source Diode Characteristics

٧	/ _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.1 \text{ A}$ (Note 2)		0.6	1.2	V
t	rr	Reverse Recovery Time	_F = 5.3 A, di/dt = 100 A/μs		18	32	ns
C	Q _{rr}	Reverse Recovery Charge			4.6	10	nC

Notes: 1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 65 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 133 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < $300\mu s,$ Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

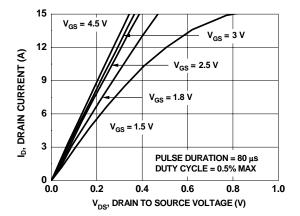


Figure 1. On-Region Characteristics

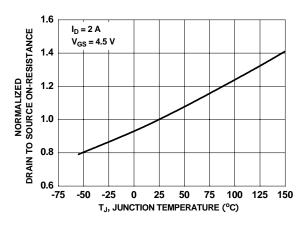


Figure 3. Normalized On-Resistance vs Junction Temperature

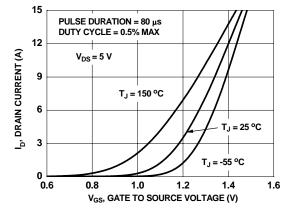


Figure 5. Transfer Characteristics

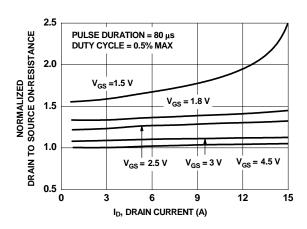


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

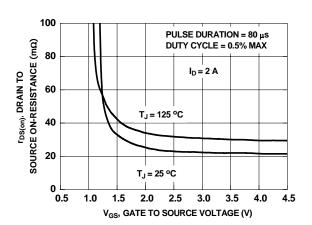


Figure 4. On-Resistance vs Gate to Source Voltage

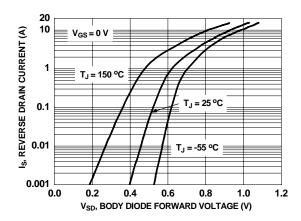


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

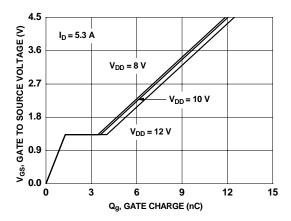


Figure 7. Gate Charge Characteristics

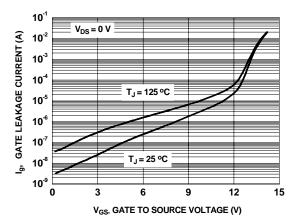


Figure 9. Gate Leakage Current vs Gate to Source Voltage

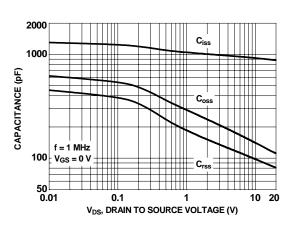


Figure 8. Capacitance vs Drain to Source Voltage

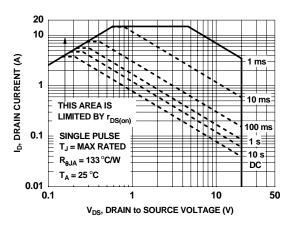


Figure 10. Forward Bias Safe Operating Area

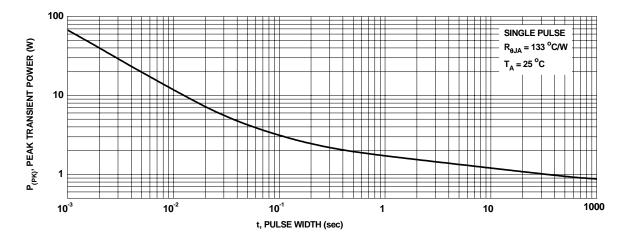


Figure 11. Single Pulse Maximum Power Dissipation

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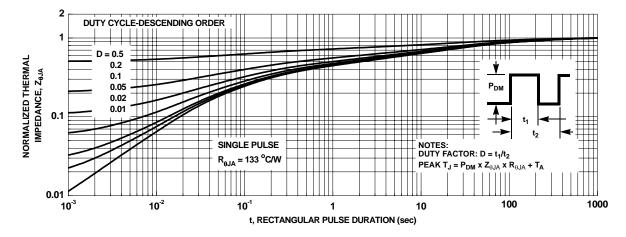
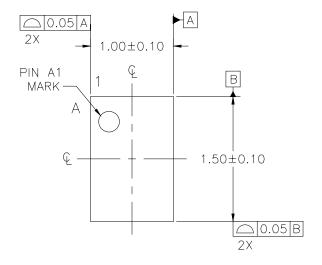
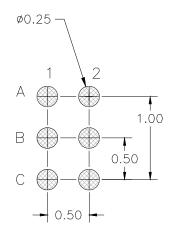
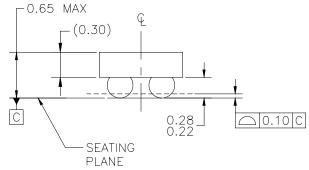


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

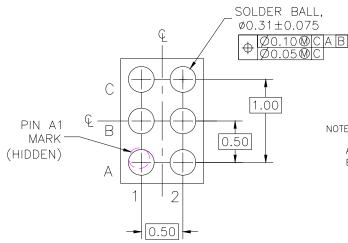
Dimensional Outline and Pad Layout











NOTES: UNLESS OTHERWISE SPECIFIED

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